

TA Technology (Shanghai) Co., Ltd.
Test Report

No. RZA2008-1085FCC

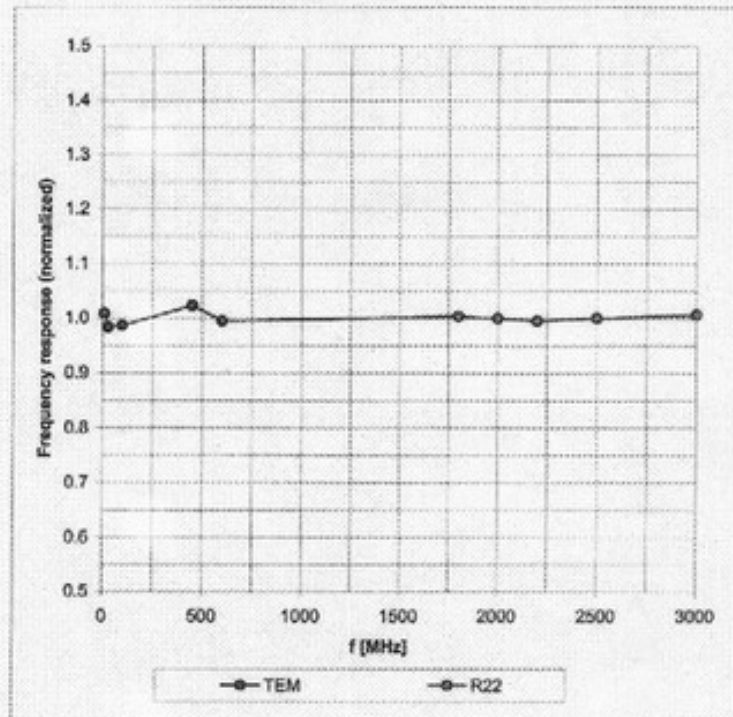
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Frequency Response of E-Field

(TEM-Cell: If110 EXX, Waveguide: R22)



Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)

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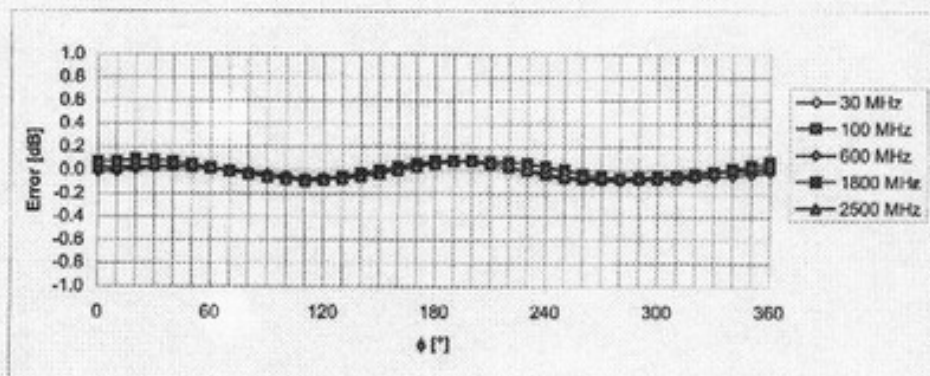
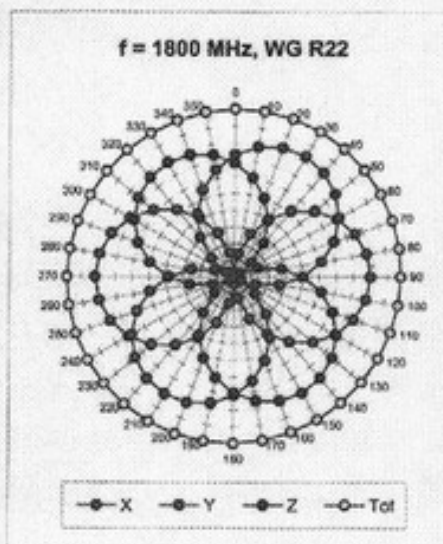
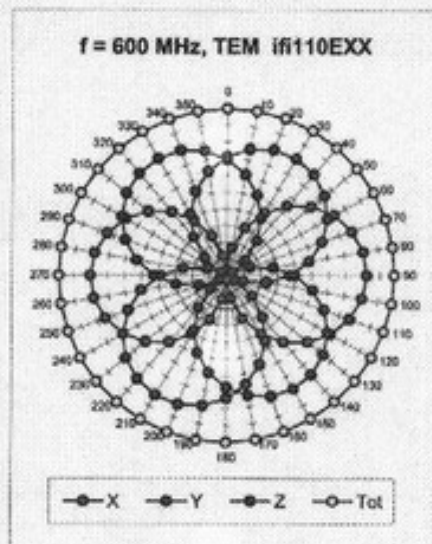
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Receiving Pattern (ϕ), $\theta = 0^\circ$



Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ ($k=2$)

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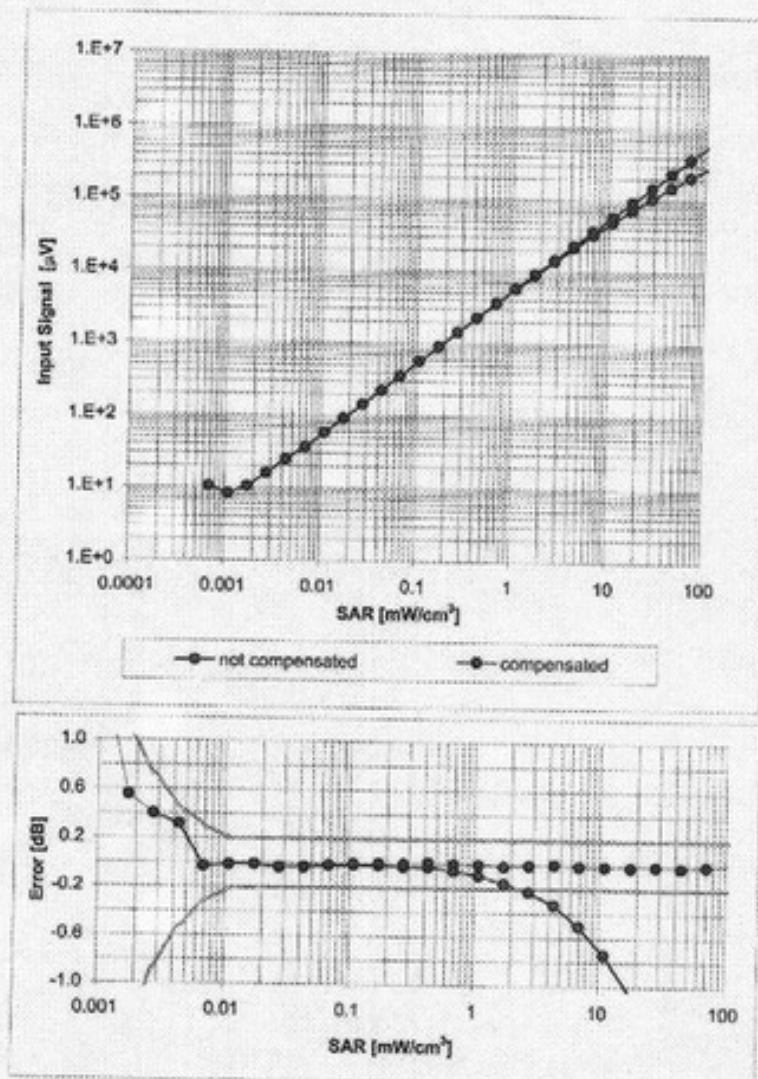
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Dynamic Range $f(\text{SAR}_{\text{head}})$
(Waveguide R22, $f = 1800 \text{ MHz}$)



Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)